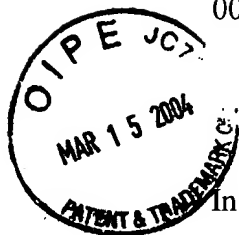


00169.001922.

PATENT APPLICATION



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

SUE-KEN YAP

Application No.: 09/737,749

Filed: December 18, 2000

For: CONTEXT SENSITIVE
INFORMATION ACCESS
ARTIFACTS

Examiner: L. Caputo

Group Art Unit: 2876

March 10, 2004

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed below and on the enclosed Form PTO-1449. Copies of the listed documents are also enclosed.

- (1) U.S. Patent No. 5,002,062
- (2) U.S. Patent No. 5,353,016
- (3) U.S. Patent No. 5,601,489
- (4) U.S. Patent No. 5,949,492
- (5) U.S. Patent No. 5,973,475
- (6) U.S. Patent No. 6,014,593
- (7) U.S. Patent No. 6,229,694

I hereby certify that this correspondence is being deposited with the United States Postal Service as first-class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on

March 10, 2004
(Date of Deposit)

Edward A. Kmetz, Reg. No. 42,746
(Name of Attorney for Applicant)

Signature

March 10, 2004
Date of Signature


- (8) WO 95/35534
- (9) Germany 36 37 684
- (10) Japan 59-123986
- (11) Japan 4-88547
- (12) Japan 3-71329

English language abstracts for each of documents (8) through (12) have been located and are enclosed for the Examiner's consideration. The concise explanation of relevance for each of the non-English language documents is believed to be satisfied by the enclosed English language abstracts. See MPEP § 609.

Inasmuch as this Information Disclosure Statement is filed concurrently with a Request for Continued Examination, it is believed that this Information Disclosure Statement is timely. See 37 C.F.R. § 1.97(b)(4). Accordingly, the Examiner is urged to study this information in its entirety and to form an independent determination of the materiality of the information to the claimed invention. Additionally, the Examiner is requested to indicate that this information has been considered by initialing the appropriate portion of the enclosed Form PTO-1449 and returning the initialed form to Applicants with the next communication.

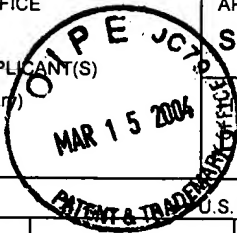
Applicant's undersigned attorney may be reached in our Costa Mesa, California office by telephone at (714) 540-8700. All correspondence should continue to be directed to our address given below.

Respectfully submitted,



Attorney for Applicant
Registration No. 42,746

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FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 00169.0001922.		APPLICATION NO. 09/737,749	
				APPLICANT SUE-KEN YAP			
				FILING DATE December 18, 2000		GROUP 2876	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		5,002,062	03/26/1991	Suzuki	128	696	
		5,353,016	10/04/1994	Kurita et al.	340	825	
		5,601,489	02/11/1997	Komaki	463	44	
		5,949,492	09/07/1999	Mankovitz	348	473	
		5,973,475	10/26/1999	Combaluzier	320	107	
		6,014,593	01/11/00	Gruzman	700	136	
		6,229,694	05/08/2001	Kono	361	683	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
	WO	95/35534	12/28/1995	PCT			Abstract
	DE	36 37 684	05/07/1987	Germany			Abstract
	JP	59-123986	07/17/1984	Japan			Abstract
	JP	4-88547	03/23/1992	Japan			Abstract
	JP	3-71329	03/27/1991	Japan			Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER				DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.